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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Obsolete
Number of LABs/CLBs	120
Number of Logic Elements/Cells	480
Total RAM Bits	-
Number of I/O	81
Number of Gates	6000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc5204-6vq100c

single-length lines, double-length lines, and Longlines all routed through the GRM. The direct connects, LIM, and logic-cell feedthrough are contained within each Versa-Block. Throughout the XC5200 interconnect, an efficient multiplexing scheme, in combination with three layer metal (TLM), was used to improve the overall efficiency of silicon usage.

Performance Overview

The XC5200 family has been benchmarked with many designs running synchronous clock rates beyond 66 MHz. The performance of any design depends on the circuit to be implemented, and the delay through the combinatorial and sequential logic elements, plus the delay in the interconnect routing. A rough estimate of timing can be made by assuming 3-6 ns per logic level, which includes direct-connect routing delays, depending on speed grade. More accurate estimations can be made using the information in the Switching Characteristic Guideline section.

Taking Advantage of Reconfiguration

FPGA devices can be reconfigured to change logic function while resident in the system. This capability gives the system designer a new degree of freedom not available with any other type of logic.

Hardware can be changed as easily as software. Design updates or modifications are easy, and can be made to products already in the field. An FPGA can even be reconfigured dynamically to perform different functions at different times.

Reconfigurable logic can be used to implement system self-diagnostics, create systems capable of being reconfigured for different environments or operations, or implement multi-purpose hardware for a given application. As an added benefit, using reconfigurable FPGA devices simplifies hardware design and debugging and shortens product time-to-market.

Detailed Functional Description

Configurable Logic Blocks (CLBs)

Figure 4 shows the logic in the XC5200 CLB, which consists of four Logic Cells (LC[3:0]). Each Logic Cell consists of an independent 4-input Lookup Table (LUT), and a D-Type flip-flop or latch with common clock, clock enable, and clear, but individually selectable clock polarity. Additional logic features provided in the CLB are:

- An independent 5-input LUT by combining two 4-input LUTs.
- High-speed carry propagate logic.
- High-speed pattern decoding.
- High-speed direct connection to flip-flop D-inputs.
- Individual selection of either a transparent, level-sensitive latch or a D flip-flop.
- Four 3-state buffers with a shared Output Enable.

5-Input Functions

Figure 5 illustrates how the outputs from the LUTs from LC0 and LC1 can be combined with a 2:1 multiplexer (F5_MUX) to provide a 5-input function. The outputs from the LUTs of LC2 and LC3 can be similarly combined.

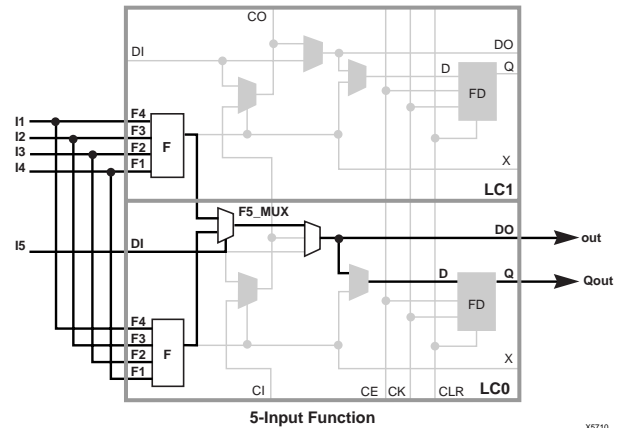


Figure 5: Two LUTs in Parallel Combined to Create a 5-input Function

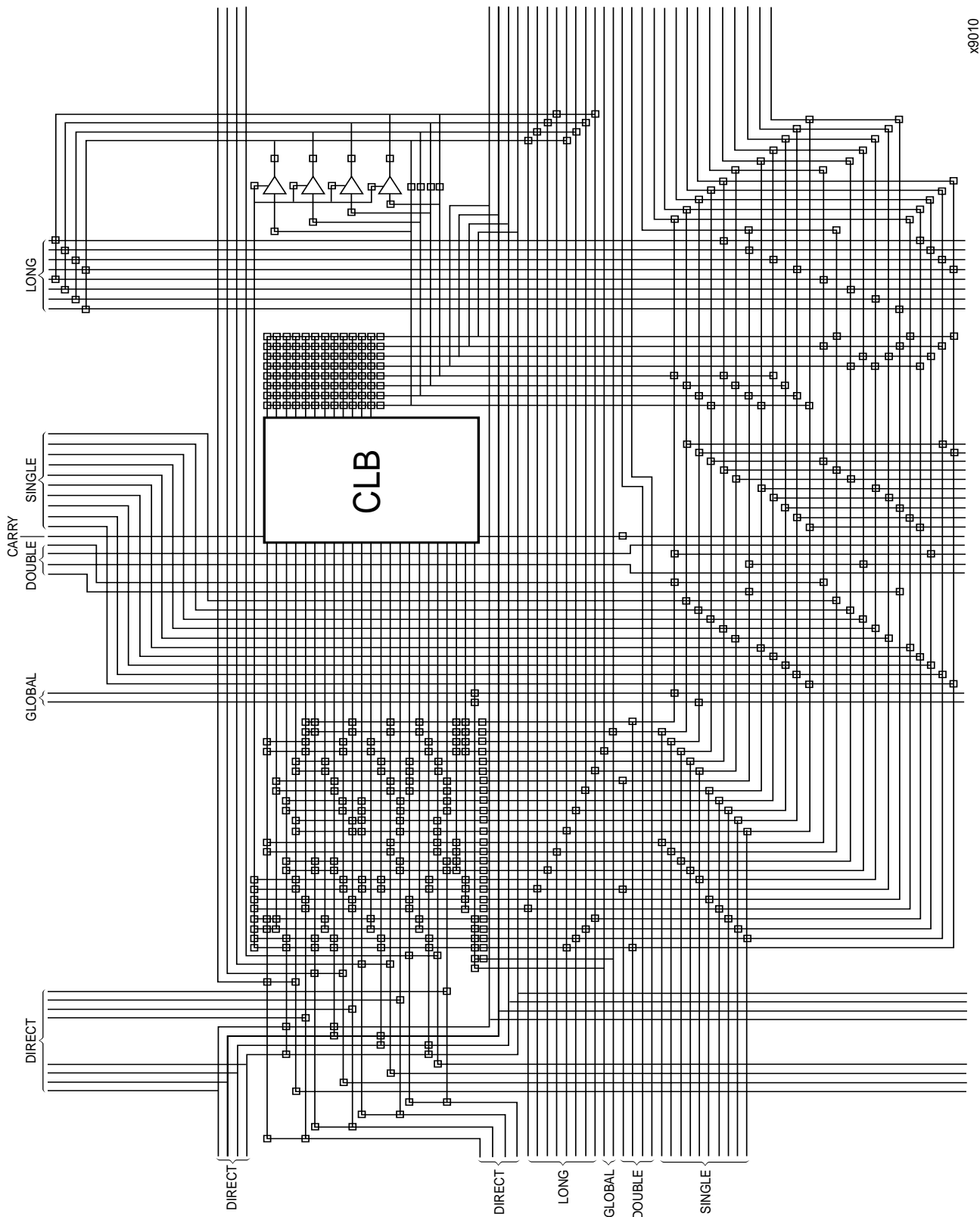


Figure 17: Detail of Programmable Interconnect Associated with XC5200 Series CLB

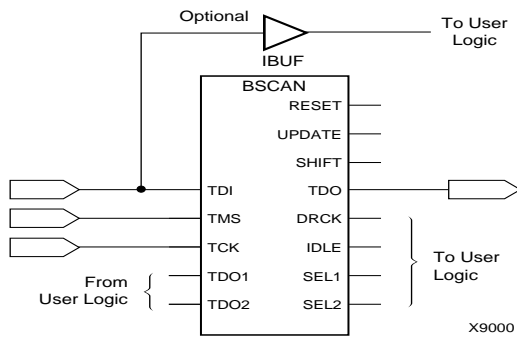


Figure 20: Boundary Scan Schematic Example

Even if the boundary scan symbol is used in a schematic, the input pins TMS, TCK, and TDI can still be used as inputs to be routed to internal logic. Care must be taken not to force the chip into an undesired boundary scan state by inadvertently applying boundary scan input patterns to these pins. The simplest way to prevent this is to keep TMS High, and then apply whatever signal is desired to TDI and TCK.

Avoiding Inadvertent Boundary Scan

If TMS or TCK is used as user I/O, care must be taken to ensure that at least one of these pins is held constant during configuration. In some applications, a situation may occur where TMS or TCK is driven during configuration. This may cause the device to go into boundary scan mode and disrupt the configuration process.

To prevent activation of boundary scan during configuration, do either of the following:

- TMS: Tie High to put the Test Access Port controller in a benign RESET state
- TCK: Tie High or Low—do not toggle this clock input.

For more information regarding boundary scan, refer to the Xilinx Application Note XAPP 017, "Boundary Scan in XC4000 and XC5200 Devices."

Power Distribution

Power for the FPGA is distributed through a grid to achieve high noise immunity and isolation between logic and I/O. Inside the FPGA, a dedicated Vcc and Ground ring surrounding the logic array provides power to the I/O drivers, as shown in [Figure 21](#). An independent matrix of Vcc and Ground lines supplies the interior logic of the device.

This power distribution grid provides a stable supply and ground for all internal logic, providing the external package power pins are all connected and appropriately decoupled.

Typically, a 0.1 μ F capacitor connected near the Vcc and Ground pins of the package will provide adequate decoupling.

Output buffers capable of driving/sinking the specified 8 mA loads under specified worst-case conditions may be capable of driving/sinking up to 10 times as much current under best case conditions.

Noise can be reduced by minimizing external load capacitance and reducing simultaneous output transitions in the same direction. It may also be beneficial to locate heavily loaded output buffers near the Ground pads. The I/O Block output buffers have a slew-rate limited mode (default) which should be used where output rise and fall times are not speed-critical.

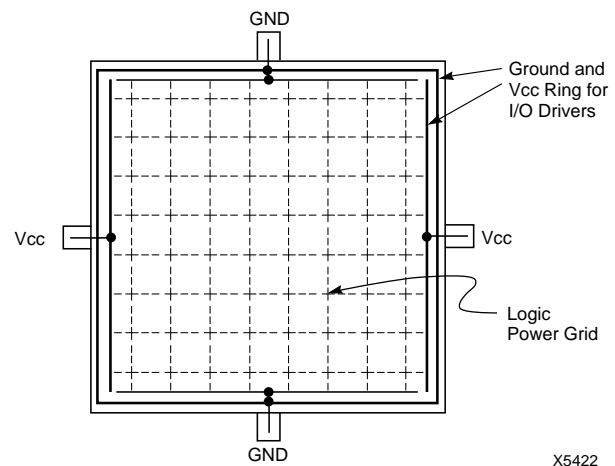


Figure 21: XC5200-Series Power Distribution

Pin Descriptions

There are three types of pins in the XC5200-Series devices:

- Permanently dedicated pins
- User I/O pins that can have special functions
- Unrestricted user-programmable I/O pins.

Before and during configuration, all outputs not used for the configuration process are 3-stated and pulled high with a 20 k Ω - 100 k Ω pull-up resistor.

After configuration, if an IOB is unused it is configured as an input with a 20 k Ω - 100 k Ω pull-up resistor.

Device pins for XC5200-Series devices are described in [Table 9](#). Pin functions during configuration for each of the seven configuration modes are summarized in "Pin Func-

tions During Configuration" on page 124, in the "Configuration Timing" section.

Table 9: Pin Descriptions

Pin Name	I/O During Config.	I/O After Config.	Pin Description
Permanently Dedicated Pins			
VCC	I	I	Five or more (depending on package) connections to the nominal +5 V supply voltage. All must be connected, and each must be decoupled with a 0.01 - 0.1 μ F capacitor to Ground.
GND	I	I	Four or more (depending on package type) connections to Ground. All must be connected.
CCLK	I or O	I	During configuration, Configuration Clock (CCLK) is an output in Master modes or Asynchronous Peripheral mode, but is an input in Slave mode, Synchronous Peripheral mode, and Express mode. After configuration, CCLK has a weak pull-up resistor and can be selected as the Readback Clock. There is no CCLK High time restriction on XC5200-Series devices, except during Readback. See "Violating the Maximum High and Low Time Specification for the Readback Clock" on page 113 for an explanation of this exception.
DONE	I/O	O	DONE is a bidirectional signal with an optional internal pull-up resistor. As an output, it indicates the completion of the configuration process. As an input, a Low level on DONE can be configured to delay the global logic initialization and the enabling of outputs. The exact timing, the clock source for the Low-to-High transition, and the optional pull-up resistor are selected as options in the program that creates the configuration bit-stream. The resistor is included by default.
$\overline{\text{PROGRAM}}$	I	I	PROGRAM is an active Low input that forces the FPGA to clear its configuration memory. It is used to initiate a configuration cycle. When PROGRAM goes High, the FPGA executes a complete clear cycle, before it goes into a WAIT state and releases INIT. The PROGRAM pin has an optional weak pull-up after configuration.
User I/O Pins That Can Have Special Functions			
RDY/ $\overline{\text{BUSY}}$	O	I/O	During Peripheral mode configuration, this pin indicates when it is appropriate to write another byte of data into the FPGA. The same status is also available on D7 in Asynchronous Peripheral mode, if a read operation is performed when the device is selected. After configuration, RDY/ $\overline{\text{BUSY}}$ is a user-programmable I/O pin. RDY/ $\overline{\text{BUSY}}$ is pulled High with a high-impedance pull-up prior to INIT going High.
$\overline{\text{RCLK}}$	O	I/O	During Master Parallel configuration, each change on the A0-A17 outputs is preceded by a rising edge on RCLK, a redundant output signal. RCLK is useful for clocked PROMs. It is rarely used during configuration. After configuration, RCLK is a user-programmable I/O pin.
M0, M1, M2	I	I/O	As Mode inputs, these pins are sampled before the start of configuration to determine the configuration mode to be used. After configuration, M0, M1, and M2 become user-programmable I/O. During configuration, these pins have weak pull-up resistors. For the most popular configuration mode, Slave Serial, the mode pins can thus be left unconnected. A pull-down resistor value of 3.3 k Ω is recommended for other modes.
TDO	O	O	If boundary scan is used, this pin is the Test Data Output. If boundary scan is not used, this pin is a 3-state output, after configuration is completed. This pin can be user output only when called out by special schematic definitions. To use this pin, place the library component TDO instead of the usual pad symbol. An output buffer must still be used.

Table 9: Pin Descriptions (Continued)

Pin Name	I/O During Config.	I/O After Config.	Pin Description
TDI, TCK, TMS	I	I/O or I (JTAG)	If boundary scan is used, these pins are Test Data In, Test Clock, and Test Mode Select inputs respectively. They come directly from the pads, bypassing the IOBs. These pins can also be used as inputs to the CLB logic after configuration is completed. If the BSCAN symbol is not placed in the design, all boundary scan functions are inhibited once configuration is completed, and these pins become user-programmable I/O. In this case, they must be called out by special schematic definitions. To use these pins, place the library components TDI, TCK, and TMS instead of the usual pad symbols. Input or output buffers must still be used.
HDC	O	I/O	High During Configuration (HDC) is driven High until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, HDC is a user-programmable I/O pin.
$\overline{\text{LDC}}$	O	I/O	Low During Configuration (LDC) is driven Low until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, LDC is a user-programmable I/O pin.
$\overline{\text{INIT}}$	I/O	I/O	Before and during configuration, $\overline{\text{INIT}}$ is a bidirectional signal. A 1 k Ω - 10 k Ω external pull-up resistor is recommended. As an active-Low open-drain output, $\overline{\text{INIT}}$ is held Low during the power stabilization and internal clearing of the configuration memory. As an active-Low input, it can be used to hold the FPGA in the internal WAIT state before the start of configuration. Master mode devices stay in a WAIT state an additional 50 to 250 μs after INIT has gone High. During configuration, a Low on this output indicates that a configuration data error has occurred. After the I/O go active, INIT is a user-programmable I/O pin.
GCK1 - GCK4	Weak Pull-up	I or I/O	Four Global inputs each drive a dedicated internal global net with short delay and minimal skew. These internal global nets can also be driven from internal logic. If not used to drive a global net, any of these pins is a user-programmable I/O pin. The GCK1-GCK4 pins provide the shortest path to the four Global Buffers. Any input pad symbol connected directly to the input of a BUFG symbol is automatically placed on one of these pins.
$\overline{\text{CS0}}$, $\overline{\text{CS1}}$, $\overline{\text{WS}}$, $\overline{\text{RS}}$	I	I/O	These four inputs are used in Asynchronous Peripheral mode. The chip is selected when $\overline{\text{CS0}}$ is Low and $\overline{\text{CS1}}$ is High. While the chip is selected, a Low on Write Strobe ($\overline{\text{WS}}$) loads the data present on the D0 - D7 inputs into the internal data buffer. A Low on Read Strobe ($\overline{\text{RS}}$) changes D7 into a status output — High if Ready, Low if Busy — and drives D0 - D6 High. In Express mode, CS1 is used as a serial-enable signal for daisy-chaining. $\overline{\text{WS}}$ and $\overline{\text{RS}}$ should be mutually exclusive, but if both are Low simultaneously, the Write Strobe overrides. After configuration, these are user-programmable I/O pins.
A0 - A17	O	I/O	During Master Parallel configuration, these 18 output pins address the configuration EPROM. After configuration, they are user-programmable I/O pins.
D0 - D7	I	I/O	During Master Parallel, Peripheral, and Express configuration, these eight input pins receive configuration data. After configuration, they are user-programmable I/O pins.
DIN	I	I/O	During Slave Serial or Master Serial configuration, DIN is the serial configuration data input receiving data on the rising edge of CCLK. During Parallel configuration, DIN is the D0 input. After configuration, DIN is a user-programmable I/O pin.
DOUT	O	I/O	During configuration in any mode but Express mode, DOUT is the serial configuration data output that can drive the DIN of daisy-chained slave FPGAs. DOUT data changes on the falling edge of CCLK. In Express mode, DOUT is the status output that can drive the CS1 of daisy-chained FPGAs, to enable and disable downstream devices. After configuration, DOUT is a user-programmable I/O pin.

Master Serial Mode

In Master Serial mode, the CCLK output of the lead FPGA drives a Xilinx Serial PROM that feeds the FPGA DIN input. Each rising edge of the CCLK output increments the Serial PROM internal address counter. The next data bit is put on the SPROM data output, connected to the FPGA DIN pin. The lead FPGA accepts this data on the subsequent rising CCLK edge.

The lead FPGA then presents the preamble data—and all data that overflows the lead device—on its DOUT pin. There is an internal pipeline delay of 1.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

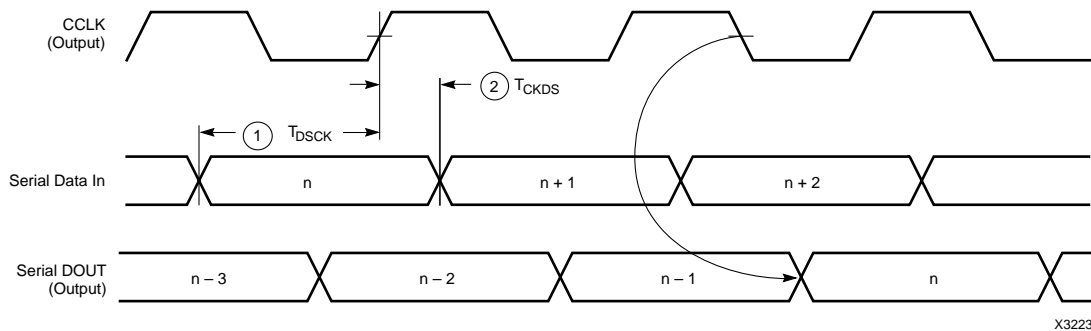
In the bitstream generation software, the user can specify Fast ConfigRate, which, starting several bits into the first frame, increases the CCLK frequency by a factor of twelve.

The value increases from a nominal 1 MHz, to a nominal 12 MHz. Be sure that the serial PROM and slaves are fast enough to support this data rate. The Medium ConfigRate option changes the frequency to a nominal 6 MHz. XC2000, XC3000/A, and XC3100A devices do not support the Fast or Medium ConfigRate options.

The SPROM $\overline{\text{CE}}$ input can be driven from either $\overline{\text{LDC}}$ or $\overline{\text{DONE}}$. Using $\overline{\text{LDC}}$ avoids potential contention on the DIN pin, if this pin is configured as user-I/O, but $\overline{\text{LDC}}$ is then restricted to be a permanently High user output after configuration. Using $\overline{\text{DONE}}$ can also avoid contention on DIN, provided the $\overline{\text{DONE}}$ before I/O enable option is invoked.

Figure 28 on page 114 shows a full master/slave system. The leftmost device is in Master Serial mode.

Master Serial mode is selected by a <000> on the mode pins (M2, M1, M0).



	Description	Symbol	Min	Max	Units
CCLK	DIN setup	1 T_{DSCK}	20		ns
	DIN hold	2 T_{CKDS}	0		ns

Notes: 1. At power-up, V_{CC} must rise from 2.0 V to V_{CC} min in less than 25 ms, otherwise delay configuration by pulling $\overline{\text{PROGRAM}}$ Low until V_{CC} is valid.
2. Master Serial mode timing is based on testing in slave mode.

Figure 30: Master Serial Mode Programming Switching Characteristics

In the two Master Parallel modes, the lead FPGA directly addresses an industry-standard byte-wide EPROM, and accepts eight data bits just before incrementing or decrementing the address outputs.

The eight data bits are serialized in the lead FPGA, which then presents the preamble data—and all data that overflows the lead device—on its DOUT pin. There is an internal delay of 1.5 CCLK periods, after the rising CCLK edge that accepts a byte of data (and also changes the EPROM address) until the falling CCLK edge that makes the LSB (D0) of this byte appear at DOUT. This means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

The PROM address pins can be incremented or decremented, depending on the mode pin settings. This option allows the FPGA to share the PROM with a wide variety of microprocessors and microcontrollers. Some processors must boot from the bottom of memory (all zeros) while others must boot from the top. The FPGA is flexible and can load its configuration bitstream from either end of the memory.

Master Parallel Up mode is selected by a <100> on the mode pins (M2, M1, M0). The EPROM addresses start at 00000 and increment.

Master Parallel Down mode is selected by a <110> on the mode pins. The EPROM addresses start at 3FFFF and decrement.

Synchronous Peripheral Mode

Synchronous Peripheral mode can also be considered Slave Parallel mode. An external signal drives the CCLK input(s) of the FPGA(s). The first byte of parallel configuration data must be available at the Data inputs of the lead FPGA a short setup time before the rising CCLK edge. Subsequent data bytes are clocked in on every eighth consecutive rising CCLK edge.

The same CCLK edge that accepts data, also causes the RDY/BUSY output to go High for one CCLK period. The pin name is a misnomer. In Synchronous Peripheral mode it is really an ACKNOWLEDGE signal. Synchronous operation does not require this response, but it is a meaningful signal

for test purposes. Note that RDY/BUSY is pulled High with a high-impedance pullup prior to INIT going High.

The lead FPGA serializes the data and presents the preamble data (and all data that overflows the lead device) on its DOUT pin. There is an internal delay of 1.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

In order to complete the serial shift operation, 10 additional CCLK rising edges are required after the last data byte has been loaded, plus one more CCLK cycle for each daisy-chained device.

Synchronous Peripheral mode is selected by a <011> on the mode pins (M2, M1, M0).

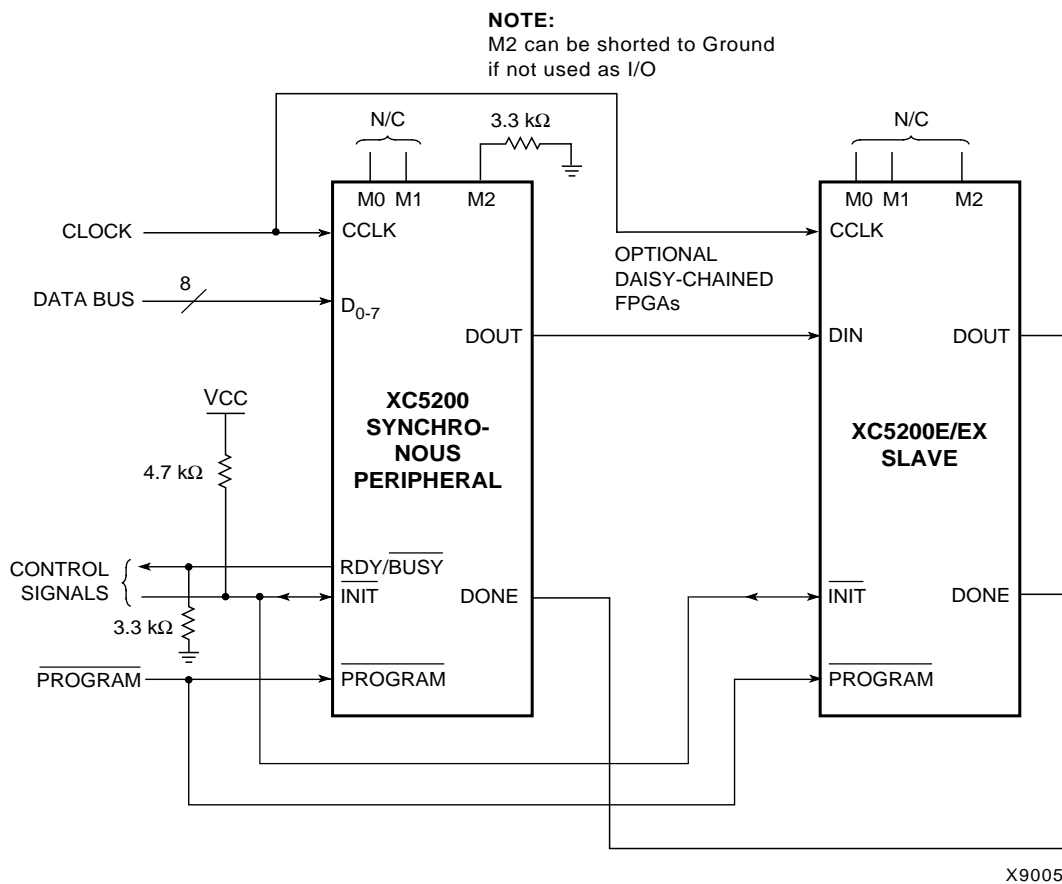


Figure 33: Synchronous Peripheral Mode Circuit Diagram

Express Mode

Express mode is similar to Slave Serial mode, except that data is processed one byte per CCLK cycle instead of one bit per CCLK cycle. An external source is used to drive CCLK, while byte-wide data is loaded directly into the configuration data shift registers. A CCLK frequency of 10 MHz is equivalent to an 80 MHz serial rate, because eight bits of configuration data are loaded per CCLK cycle. Express mode does not support CRC error checking, but does support constant-field error checking.

In Express mode, an external signal drives the CCLK input of the FPGA device. The first byte of parallel configuration data must be available at the D inputs of the FPGA a short setup time before the second rising CCLK edge. Subsequent data bytes are clocked in on each consecutive rising CCLK edge.

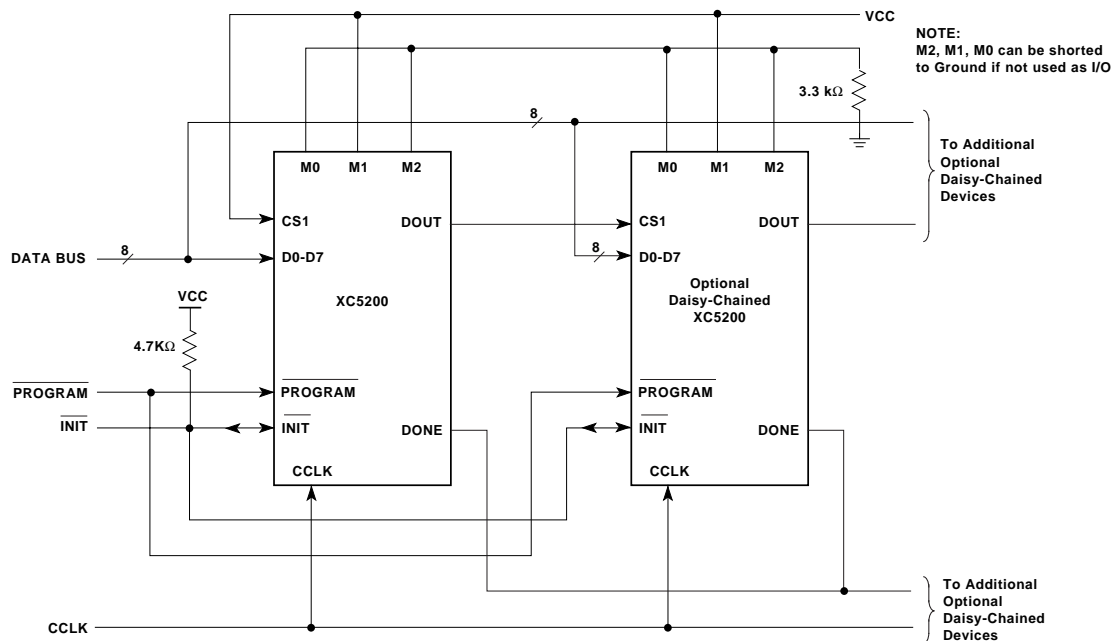
If the first device is configured in Express mode, additional devices may be daisy-chained only if every device in the chain is also configured in Express mode. CCLK pins are tied together and D0-D7 pins are tied together for all devices along the chain. A status signal is passed from DOUT to CS1 of successive devices along the chain. The lead device in the chain has its CS1 input tied High (or floating, since there is an internal pullup). Frame data is accepted only when CS1 is High and the device's configu-

ration memory is not already full. The status pin DOUT is pulled Low two internal-oscillator cycles after INIT is recognized as High, and remains Low until the device's configuration memory is full. DOUT is then pulled High to signal the next device in the chain to accept the configuration data on the D0-D7 bus.

The DONE pins of all devices in the chain should be tied together, with one or more active internal pull-ups. If a large number of devices are included in the chain, deactivate some of the internal pull-ups, since the Low-driving DONE pin of the last device in the chain must sink the current from all pull-ups in the chain. The DONE pull-up is activated by default. It can be deactivated using an option in the bitstream generation software.

XC5200 devices in Express mode are always synchronized to DONE. The device becomes active after DONE goes High. DONE is an open-drain output. With the DONE pins tied together, therefore, the external DONE signal stays low until all devices are configured, then all devices in the daisy chain become active simultaneously. If the DONE pin of a device is left unconnected, the device becomes active as soon as that device has been configured.

Express mode is selected by a <010> on the mode pins (M2, M1, M0).



X6611_01

Figure 37: Express Mode Circuit Diagram

Product Obsolete or Under Obsolescence

XC5200 Series Field Programmable Gate Arrays



Table 13. Pin Functions During Configuration

CONFIGURATION MODE: <M2:M1:M0>							USER OPERATION
SLAVE <1:1:1>	MASTER-SER <0:0:0>	SYN.PERIPH <0:1:1>	ASYN.PERIPH <1:0:1>	MASTER-HIGH <1:1:0>	MASTER-LOW <1:0:0>	EXPRESS <0:1:0>	
				A16	A16		GCK1-I/O
				A17	A17		I/O
TDI	TDI	TDI	TDI	TDI	TDI	TDI	TDI-I/O
TCK	TCK	TCK	TCK	TCK	TCK	TCK	TCK-I/O
TMS	TMS	TMS	TMS	TMS	TMS	TMS	TMS-I/O
							I/O
M1 (HIGH) (I)	M1 (LOW) (I)	M1 (HIGH) (I)	M1 (LOW) (I)	M1 (HIGH) (I)	M1 (LOW) (I)	M1 (HIGH) (I)	I/O
M0 (HIGH) (I)	M0 (LOW) (I)	M0 (HIGH) (I)	M0 (HIGH) (I)	M0 (LOW) (I)	M0 (LOW) (I)	M0 (LOW) (I)	I/O
M2 (HIGH) (I)	M2 (LOW) (I)	M2 (LOW) (I)	M2 (HIGH) (I)	M2 (HIGH) (I)	M2 (HIGH) (I)	M2 (LOW) (I)	I/O
							GCK2-I/O
HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	I/O
LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	I/O
INIT-ERROR	INIT-ERROR	INIT-ERROR	INIT-ERROR	INIT-ERROR	INIT-ERROR	INIT-ERROR	I/O
							I/O
DONE	DONE	DONE	DONE	DONE	DONE	DONE	DONE
PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM
		DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	I/O
							GCK3-I/O
		DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	I/O
		DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	I/O
			CS0 (I)				I/O
		DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	I/O
		DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	I/O
			RS (I)				I/O
		DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	I/O
		DATA 1 (I)	DATA 1 (I)	DATA 1 (I)	DATA 1 (I)	DATA 1 (I)	I/O
		RDY/BUSY	RDY/BUSY	RCLK	RCLK		I/O
DIN (I)	DIN (I)	DATA 0 (I)	DATA 0 (I)	DATA 0 (I)	DATA 0 (I)	DATA 0 (I)	I/O
DOUT	DOUT	DOUT	DOUT	DOUT	DOUT	DOUT	I/O
CCLK (I)	CCLK (O)	CCLK (I)	CCLK (O)	CCLK (O)	CCLK (O)	CCLK (I)	CCLK (I)
TDO	TDO	TDO	TDO	TDO	TDO	TDO	TDO-I/O
			WS (I)	A0	A0		I/O
				A1	A1		GCK4-I/O
			CS1 (I)	A2	A2	CS1 (I)	I/O
				A3	A3		I/O
				A4	A4		I/O
				A5	A5		I/O
				A6	A6		I/O
				A7	A7		I/O
				A8	A8		I/O
				A9	A9		I/O
				A10	A10		I/O
				A11	A11		I/O
				A12	A12		I/O
				A13	A13		I/O
				A14	A14		I/O
				A15	A15		I/O
							ALL OTHERS

- Notes:**
1. A shaded table cell represents a 20-kΩ to 100-kΩ pull-up resistor before and during configuration.
 2. (I) represents an input (O) represents an output.
 3. INIT is an open-drain output during configuration.

XC5200 CLB Switching Characteristic Guidelines

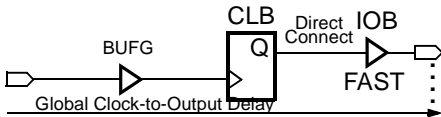
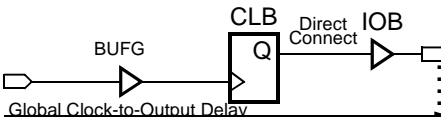
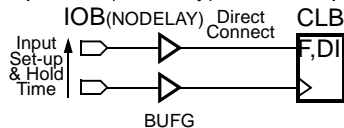
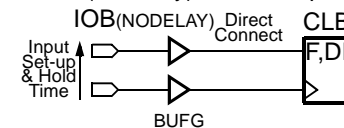
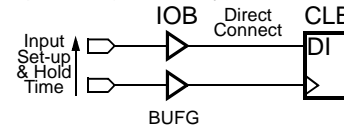
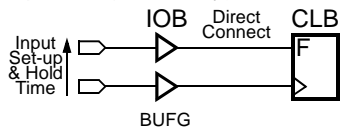
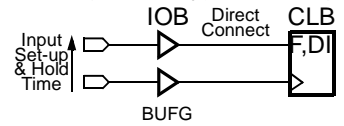
Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100% functionally tested. Since many internal timing parameters cannot be measured directly, they are derived from benchmark timing patterns. The following guidelines reflect worst-case values over the recommended operating conditions. For more detailed, more precise, and more up-to-date timing information, use the values provided by the timing calculator and used in the simulator.

Speed Grade		-6		-5		-4		-3	
Description	Symbol	Min (ns)	Max (ns)	Min (ns)	Max (ns)	Min (ns)	Max (ns)	Min (ns)	Max (ns)
Combinatorial Delays									
F inputs to X output	T_{ILO}		5.6		4.6		3.8		3.0
F inputs via transparent latch to Q	T_{ITO}		8.0		6.6		5.4		4.3
DI inputs to DO output (Logic-Cell Feedthrough)	T_{IDO}		4.3		3.5		2.8		2.4
F inputs via F5_MUX to DO output	T_{IMO}		7.2		5.8		5.0		4.3
Carry Delays									
Incremental delay per bit	T_{CY}		0.7		0.6		0.5		0.5
Carry-in overhead from DI	T_{CYDI}		1.8		1.6		1.5		1.4
Carry-in overhead from F	T_{CYL}		3.7		3.2		2.9		2.4
Carry-out overhead to DO	T_{CYO}		4.0		3.2		2.5		2.1
Sequential Delays									
Clock (CK) to out (Q) (Flip-Flop)	T_{CKO}		5.8		4.9		4.0		4.0
Gate (Latch enable) going active to out (Q)	T_{GO}		9.2		7.4		5.9		5.5
Set-up Time Before Clock (CK)									
F inputs	T_{ICK}	2.3		1.8		1.4		1.3	
F inputs via F5_MUX	T_{MICK}	3.8		3.0		2.5		2.4	
DI input	T_{DICK}	0.8		0.5		0.4		0.4	
CE input	T_{EICK}	1.6		1.2		0.9		0.9	
Hold Times After Clock (CK)									
F inputs	T_{CKI}	0		0		0		0	
F inputs via F5_MUX	T_{CKMI}	0		0		0		0	
DI input	T_{CKDI}	0		0		0		0	
CE input	T_{CKEI}	0		0		0		0	
Clock Widths									
Clock High Time	T_{CH}	6.0		6.0		6.0		6.0	
Clock Low Time	T_{CL}	6.0		6.0		6.0		6.0	
Toggle Frequency (MHz) (Note 3)	F_{TOG}		83		83		83		83
Reset Delays									
Width (High)	$T_{CLR\overline{W}}$	6.0		6.0		6.0		6.0	
Delay from CLR to Q (Flip-Flop)	T_{CLR}		7.7		6.3		5.1		4.0
Delay from CLR to Q (Latch)	$T_{CLR\overline{L}}$		6.5		5.2		4.2		3.0
Global Reset Delays									
Width (High)	$T_{GCLR\overline{W}}$	6.0		6.0		6.0		6.0	
Delay from internal GR to Q	T_{GCLR}		14.7		12.1		9.1		8.0

- Note:**
1. The CLB K to Q output delay (T_{CKO}) of any CLB, plus the shortest possible interconnect delay, is always longer than the Data In hold-time requirement (T_{CKDI}) of any CLB on the same die.
 2. Timing is based upon the XC5215 device. For other devices, see Timing Calculator.
 3. Maximum flip-flop toggle rate for export control purposes.

XC5200 Guaranteed Input and Output Parameters (Pin-to-Pin)

All values listed below are tested directly, and guaranteed over the operating conditions. The same parameters can also be derived indirectly from the Global Buffer specifications. The delay calculator uses this indirect method, and may overestimate because of worst-case assumptions. When there is a discrepancy between these two methods, the values listed below should be used, and the derived values should be considered conservative overestimates.

		Speed Grade	-6	-5	-4	-3
Description	Symbol	Device	Max (ns)	Max (ns)	Max (ns)	Max (ns)
Global Clock to Output Pad (fast) 	T_{ICKOF} (Max)	XC5202	16.9	15.1	10.9	9.8
		XC5204	17.1	15.3	11.3	9.9
		XC5206	17.2	15.4	11.9	10.8
		XC5210	17.2	15.4	12.8	11.2
		XC5215	19.0	17.0	12.8	11.7
Global Clock to Output Pad (slew-limited) 	T_{ICKO} (Max)	XC5202	21.4	18.7	12.6	11.5
		XC5204	21.6	18.9	13.3	11.9
		XC5206	21.7	19.0	13.6	12.5
		XC5210	21.7	19.0	15.0	12.9
		XC5215	24.3	21.2	15.0	13.1
Input Set-up Time (no delay) to CLB Flip-Flop 	T_{PSUF} (Min)	XC5202	2.5	2.0	1.9	1.9
		XC5204	2.3	1.9	1.9	1.9
		XC5206	2.2	1.9	1.9	1.9
		XC5210	2.2	1.9	1.9	1.8
		XC5215	2.0	1.8	1.7	1.7
Input Hold Time (no delay) to CLB Flip-Flop 	T_{PHF} (Min)	XC5202	3.8	3.8	3.5	3.5
		XC5204	3.9	3.9	3.8	3.6
		XC5206	4.4	4.4	4.4	4.3
		XC5210	5.1	5.1	4.9	4.8
		XC5215	5.8	5.8	5.7	5.6
Input Set-up Time (with delay) to CLB Flip-Flop DI Input 	T_{PSU}	XC5202	7.3	6.6	6.6	6.6
		XC5204	7.3	6.6	6.6	6.6
		XC5206	7.2	6.5	6.4	6.3
		XC5210	7.2	6.5	6.0	6.0
		XC5215	6.8	5.7	5.7	5.7
Input Set-up Time (with delay) to CLB Flip-Flop F Input 	T_{PSUL} (Min)	XC5202	8.8	7.7	7.5	7.5
		XC5204	8.6	7.5	7.5	7.5
		XC5206	8.5	7.4	7.4	7.4
		XC5210	8.5	7.4	7.4	7.3
		XC5215	8.5	7.4	7.4	7.2
Input Hold Time (with delay) to CLB Flip-Flop 	T_{PH} (Min)	XC52xx	0	0	0	0

- Note:**
- These measurements assume that the CLB flip-flop uses a direct interconnect to or from the IOB. The INREG/ OUTREG properties, or XACT-Performance, can be used to assure that direct connects are used. t_{PSU} applies only to the CLB input DI that bypasses the look-up table, which only offers direct connects to IOBs on the left and right edges of the die. t_{PSUL} applies to the CLB inputs F that feed the look-up table, which offers direct connect to IOBs on all four edges, as do the CLB Q outputs.
 - When testing outputs (fast or slew-limited), half of the outputs on one side of the device are switching.

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XC5200 Series Field Programmable Gate Arrays



Pin	Description		PC84	PQ100	VQ100	TQ144	PG156	PQ160	Boundary Scan Order
14.	I/O		-	-	-	141	D3	157	129
15.	I/O (A14)		9	1	98	142	B1	158	138
16.	I/O (A15)		10	2	99	143	B2	159	141
	VCC		11	3	100	144	C3	160	-
	GND		12	4	1	1	C4	1	-
17.	GCK1 (A16, I/O)		13	5	2	2	B3	2	150
18.	I/O (A17)		14	6	3	3	A1	3	153
19.	I/O		-	-	-	4	A2	4	159
20.	I/O		-	-	-	5	C5	5	162
21.	I/O (TDI)		15	7	4	6	B4	6	165
22.	I/O (TCK)		16	8	5	7	A3	7	171
	GND		-	-	-	8	C6	10	-
23.	I/O		-	-	-	9	B5	11	174
24.	I/O		-	-	-	10	B6	12	177
25.	I/O (TMS)		17	9	6	11	A5	13	180
26.	I/O		18	10	7	12	C7	14	183
27.	I/O		-	-	-	13	B7	15	186
28.	I/O		-	11	8	14	A6	16	189
29.	I/O		19	12	9	15	A7	17	195
30.	I/O		20	13	10	16	A8	18	198
	GND		21	14	11	17	C8	19	-
	VCC		22	15	12	18	B8	20	-
31.	I/O		23	16	13	19	C9	21	201
32.	I/O		24	17	14	20	B9	22	207
33.	I/O		-	18	15	21	A9	23	210
34.	I/O		-	-	-	22	B10	24	213
35.	I/O		25	19	16	23	C10	25	219
36.	I/O		26	20	17	24	A10	26	222
37.	I/O		-	-	-	25	A11	27	225
38.	I/O		-	-	-	26	B11	28	231
	GND		-	-	-	27	C11	29	-
39.	I/O		27	21	18	28	B12	32	234
40.	I/O		-	22	19	29	A13	33	237
41.	I/O		-	-	-	30	A14	34	240
42.	I/O		-	-	-	31	C12	35	243
43.	I/O		28	23	20	32	B13	36	246
44.	I/O		29	24	21	33	B14	37	249
45.	M1 (I/O)		30	25	22	34	A15	38	258
	GND		31	26	23	35	C13	39	-
46.	M0 (I/O)		32	27	24	36	A16	40	261
	VCC		33	28	25	37	C14	41	-
47.	M2 (I/O)		34	29	26	38	B15	42	264
48.	GCK2 (I/O)		35	30	27	39	B16	43	267
49.	I/O (HDC)		36	31	28	40	D14	44	276
50.	I/O		-	-	-	41	C15	45	279
51.	I/O		-	-	-	42	D15	46	282
52.	I/O		-	32	29	43	E14	47	288
53.	I/O (LDC)		37	33	30	44	C16	48	291
54.	I/O		-	-	-	-	E15	49	294
55.	I/O		-	-	-	-	D16	50	300
	GND		-	-	-	45	F14	51	-
56.	I/O		-	-	-	46	F15	52	303

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XC5200 Series Field Programmable Gate Arrays

Pin	Description	PC84	PQ100	VQ100	TQ144	PG156	PQ160	Boundary Scan Order
57.	I/O	-	-	-	47	E16	53	306
58.	I/O	38	34	31	48	F16	54	312
59.	I/O	39	35	32	49	G14	55	315
60.	I/O	-	36	33	50	G15	56	318
61.	I/O	-	37	34	51	G16	57	324
62.	I/O	40	38	35	52	H16	58	327
63.	I/O (ERR, INIT)	41	39	36	53	H15	59	330
	VCC	42	40	37	54	H14	60	-
	GND	43	41	38	55	J14	61	-
64.	I/O	44	42	39	56	J15	62	336
65.	I/O	45	43	40	57	J16	63	339
66.	I/O	-	44	41	58	K16	64	348
67.	I/O	-	45	42	59	K15	65	351
68.	I/O	46	46	43	60	K14	66	354
69.	I/O	47	47	44	61	L16	67	360
70.	I/O	-	-	-	62	M16	68	363
71.	I/O	-	-	-	63	L15	69	366
	GND	-	-	-	64	L14	70	-
72.	I/O	-	-	-	-	N16	71	372
73.	I/O	-	-	-	-	M15	72	375
74.	I/O	48	48	45	65	P16	73	378
75.	I/O	49	49	46	66	M14	74	384
76.	I/O	-	-	-	67	N15	75	387
77.	I/O	-	-	-	68	P15	76	390
78.	I/O	50	50	47	69	N14	77	396
79.	I/O	51	51	48	70	R16	78	399
	GND	52	52	49	71	P14	79	-
	DONE	53	53	50	72	R15	80	-
	VCC	54	54	51	73	P13	81	-
	PROG	55	55	52	74	R14	82	-
80.	I/O (D7)	56	56	53	75	T16	83	408
81.	GCK3 (I/O)	57	57	54	76	T15	84	411
82.	I/O	-	-	-	77	R13	85	420
83.	I/O	-	-	-	78	P12	86	423
84.	I/O (D6)	58	58	55	79	T14	87	426
85.	I/O	-	59	56	80	T13	88	432
	GND	-	-	-	81	P11	91	-
86.	I/O	-	-	-	82	R11	92	435
87.	I/O	-	-	-	83	T11	93	438
88.	I/O (D5)	59	60	57	84	T10	94	444
89.	I/O (CS0)	60	61	58	85	P10	95	447
90.	I/O	-	62	59	86	R10	96	450
91.	I/O	-	63	60	87	T9	97	456
92.	I/O (D4)	61	64	61	88	R9	98	459
93.	I/O	62	65	62	89	P9	99	462
	VCC	63	66	63	90	R8	100	-
	GND	64	67	64	91	P8	101	-
94.	I/O (D3)	65	68	65	92	T8	102	468
95.	I/O (RS)	66	69	66	93	T7	103	471
96.	I/O	-	70	67	94	T6	104	474
97.	I/O	-	-	-	95	R7	105	480
98.	I/O (D2)	67	71	68	96	P7	106	483

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XC5200 Series Field Programmable Gate Arrays

Pin Locations for XC5206 Devices

The following table may contain pinout information for unsupported device/package combinations. Please see the availability charts elsewhere in the XC5200 Series data sheet for availability information.

Pin	Description	PC84	PQ100	VQ100	TQ144	PQ160	TQ176	PG191	PQ208	Boundary Scan Order
	VCC	2	92	89	128	142	155	J4	183	-
1.	I/O (A8)	3	93	90	129	143	156	J3	184	87
2.	I/O (A9)	4	94	91	130	144	157	J2	185	90
3.	I/O	-	95	92	131	145	158	J1	186	93
4.	I/O	-	96	93	132	146	159	H1	187	99
5.	I/O	-	-	-	-	-	160	H2	188	102
6.	I/O	-	-	-	-	-	161	H3	189	105
7.	I/O (A10)	5	97	94	133	147	162	G1	190	111
8.	I/O (A11)	6	98	95	134	148	163	G2	191	114
9.	I/O	-	-	-	135	149	164	F1	192	117
10.	I/O	-	-	-	136	150	165	E1	193	123
	GND	-	-	-	137	151	166	G3	194	-
11.	I/O	-	-	-	-	152	168	C1	197	126
12.	I/O	-	-	-	-	153	169	E2	198	129
13.	I/O (A12)	7	99	96	138	154	170	F3	199	138
14.	I/O (A13)	8	100	97	139	155	171	D2	200	141
15.	I/O	-	-	-	140	156	172	B1	201	150
16.	I/O	-	-	-	141	157	173	E3	202	153
17.	I/O (A14)	9	1	98	142	158	174	C2	203	162
18.	I/O (A15)	10	2	99	143	159	175	B2	204	165
	VCC	11	3	100	144	160	176	D3	205	-
	GND	12	4	1	1	1	1	D4	2	-
19.	GCK1 (A16, I/O)	13	5	2	2	2	2	C3	4	174
20.	I/O (A17)	14	6	3	3	3	3	C4	5	177
21.	I/O	-	-	-	4	4	4	B3	6	183
22.	I/O	-	-	-	5	5	5	C5	7	186
23.	I/O (TDI)	15	7	4	6	6	6	A2	8	189
24.	I/O (TCK)	16	8	5	7	7	7	B4	9	195
25.	I/O	-	-	-	-	8	8	C6	10	198
26.	I/O	-	-	-	-	9	9	A3	11	201
	GND	-	-	-	8	10	10	C7	14	-
27.	I/O	-	-	-	9	11	11	A4	15	207
28.	I/O	-	-	-	10	12	12	A5	16	210
29.	I/O (TMS)	17	9	6	11	13	13	B7	17	213
30.	I/O	18	10	7	12	14	14	A6	18	219
31.	I/O	-	-	-	-	-	15	C8	19	222
32.	I/O	-	-	-	-	-	16	A7	20	225
33.	I/O	-	-	-	13	15	17	B8	21	234
34.	I/O	-	11	8	14	16	18	A8	22	237
35.	I/O	19	12	9	15	17	19	B9	23	246
36.	I/O	20	13	10	16	18	20	C9	24	249
	GND	21	14	11	17	19	21	D9	25	-
	VCC	22	15	12	18	20	22	D10	26	-
37.	I/O	23	16	13	19	21	23	C10	27	255
38.	I/O	24	17	14	20	22	24	B10	28	258
39.	I/O	-	18	15	21	23	25	A9	29	261
40.	I/O	-	-	-	22	24	26	A10	30	267
41.	I/O	-	-	-	-	-	27	A11	31	270

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XC5200 Series Field Programmable Gate Arrays

Pin	Description	PC84	TQ144	PQ160	TQ176	PQ208	PG223	BG225	PQ240	Boundary Scan Order
7.	I/O (A10)	5	133	147	162	190	G1	A6	220	135
8.	I/O (A11)	6	134	148	163	191	G2	B6	221	138
	VCC	-	-	-	-	-	-	VCC*	222	-
9.	I/O	-	-	-	-	-	H4	C6	223	141
10.	I/O	-	-	-	-	-	G4	F7	224	150
11.	I/O	-	135	149	164	192	F1	A5	225	153
12.	I/O	-	136	150	165	193	E1	B5	226	162
	GND	-	137	151	166	194	G3	GND*	227	-
13.	I/O	-	-	-	-	195	F2	D6	228	165
14.	I/O	-	-	-	167	196	D1	C5	229	171
15.	I/O	-	-	152	168	197	C1	A4	230	174
16.	I/O	-	-	153	169	198	E2	E6	231	177
17.	I/O (A12)	7	138	154	170	199	F3	B4	232	183
18.	I/O (A13)	8	139	155	171	200	D2	D5	233	186
19.	I/O	-	-	-	-	-	F4	A3	234	189
20.	I/O	-	-	-	-	-	E4	C4	235	195
21.	I/O	-	140	156	172	201	B1	B3	236	198
22.	I/O	-	141	157	173	202	E3	F6	237	201
23.	I/O (A14)	9	142	158	174	203	C2	A2	238	210
24.	I/O (A15)	10	143	159	175	204	B2	C3	239	213
	VCC	11	144	160	176	205	D3	VCC*	240	-
	GND	12	1	1	1	2	D4	GND*	1	-
25.	GCK1 (A16, I/O)	13	2	2	2	4	C3	D4	2	222
26.	I/O (A17)	14	3	3	3	5	C4	B1	3	225
27.	I/O	-	4	4	4	6	B3	C2	4	231
28.	I/O	-	5	5	5	7	C5	E5	5	234
29.	I/O (TDI)	15	6	6	6	8	A2	D3	6	237
30.	I/O (TCK)	16	7	7	7	9	B4	C1	7	243
31.	I/O	-	-	8	8	10	C6	D2	8	246
32.	I/O	-	-	9	9	11	A3	G6	9	249
33.	I/O	-	-	-	-	12	B5	E4	10	255
34.	I/O	-	-	-	-	13	B6	D1	11	258
35.	I/O	-	-	-	-	-	D5	E3	12	261
36.	I/O	-	-	-	-	-	D6	E2	13	267
	GND	-	8	10	10	14	C7	GND*	14	-
37.	I/O	-	9	11	11	15	A4	F5	15	270
38.	I/O	-	10	12	12	16	A5	E1	16	273
39.	I/O (TMS)	17	11	13	13	17	B7	F4	17	279
40.	I/O	18	12	14	14	18	A6	F3	18	282
	VCC	-	-	-	-	-	-	VCC*	19	-
41.	I/O	-	-	-	-	-	D7	F2	20	285
42.	I/O	-	-	-	-	-	D8	F1	21	291
43.	I/O	-	-	-	15	19	C8	G4	23	294
44.	I/O	-	-	-	16	20	A7	G3	24	297
45.	I/O	-	13	15	17	21	B8	G2	25	306
46.	I/O	-	14	16	18	22	A8	G1	26	309
47.	I/O	19	15	17	19	23	B9	G5	27	318
48.	I/O	20	16	18	20	24	C9	H3	28	321
	GND	21	17	19	21	25	D9	GND*	29	-
	VCC	22	18	20	22	26	D10	VCC*	30	-
49.	I/O	23	19	21	23	27	C10	H4	31	327

Product Obsolete or Under Obsolescence

XC5200 Series Field Programmable Gate Arrays



Pin	Description	PC84	TQ144	PQ160	TQ176	PQ208	PG223	BG225	PQ240	Boundary Scan Order
137.	I/O	-	-	-	-	-	R11	K12	137	708
138.	I/O	-	82	92	100	120	U13	K13	138	711
139.	I/O	-	83	93	101	121	V13	K14	139	714
	VCC	-	-	-	-	-	-	VCC*	140	-
140.	I/O (D5)	59	84	94	102	122	U12	K15	141	720
141.	I/O (CS0)	60	85	95	103	123	V12	J12	142	723
142.	I/O	-	-	-	104	124	T11	J13	144	726
143.	I/O	-	-	-	105	125	U11	J14	145	732
144.	I/O	-	86	96	106	126	V11	J15	146	735
145.	I/O	-	87	97	107	127	V10	J11	147	738
146.	I/O (D4)	61	88	98	108	128	U10	H13	148	744
147.	I/O	62	89	99	109	129	T10	H14	149	747
	VCC	63	90	100	110	130	R10	VCC*	150	-
	GND	64	91	101	111	131	R9	GND*	151	-
148.	I/O (D3)	65	92	102	112	132	T9	H12	152	756
149.	I/O (RS)	66	93	103	113	133	U9	H11	153	759
150.	I/O	-	94	104	114	134	V9	G14	154	768
151.	I/O	-	95	105	115	135	V8	G15	155	771
152.	I/O	-	-	-	116	136	U8	G13	156	780
153.	I/O	-	-	-	117	137	T8	G12	157	783
154.	I/O (D2)	67	96	106	118	138	V7	G11	159	786
155.	I/O	68	97	107	119	139	U7	F15	160	792
	VCC	-	-	-	-	-	-	VCC*	161	-
156.	I/O	-	98	108	120	140	V6	F14	162	795
157.	I/O	-	99	109	121	141	U6	F13	163	798
158.	I/O	-	-	-	-	-	R8	G10	164	804
159.	I/O	-	-	-	-	-	R7	E15	165	807
	GND	-	100	110	122	142	T7	GND*	166	-
160.	I/O	-	-	-	-	-	R6	E14	167	810
161.	I/O	-	-	-	-	-	R5	F12	168	816
162.	I/O	-	-	-	-	143	V5	E13	169	819
163.	I/O	-	-	-	-	144	V4	D15	170	822
164.	I/O	-	-	111	123	145	U5	F11	171	828
165.	I/O	-	-	112	124	146	T6	D14	172	831
166.	I/O (D1)	69	101	113	125	147	V3	E12	173	834
167.	I/O (RCLK-BUSY/RDY)	70	102	114	126	148	V2	C15	174	840
168.	I/O	-	103	115	127	149	U4	D13	175	843
169.	I/O	-	104	116	128	150	T5	C14	176	846
170.	I/O (D0, DIN)	71	105	117	129	151	U3	F10	177	855
171.	I/O (DOUT)	72	106	118	130	152	T4	B15	178	858
	CCLK	73	107	119	131	153	V1	C13	179	-
	VCC	74	108	120	132	154	R4	VCC*	180	-
172.	I/O (TDO)	75	109	121	133	159	U2	A15	181	-
	GND	76	110	122	134	160	R3	GND*	182	-
173.	I/O (A0, WS)	77	111	123	135	161	T3	A14	183	9
174.	GCK4 (A1, I/O)	78	112	124	136	162	U1	B13	184	15
175.	I/O	-	113	125	137	163	P3	E11	185	18
176.	I/O	-	114	126	138	164	R2	C12	186	21
177.	I/O (CS1, A2)	79	115	127	139	165	T2	A13	187	27
178.	I/O (A3)	80	116	128	140	166	N3	B12	188	30
179.	I/O	-	-	-	-	-	P4	F9	189	33

Product Obsolete or Under Obsolescence

XC5200 Series Field Programmable Gate Arrays



Pin	Description	PQ160	HQ208	HQ240	PG299	BG225	BG352	Boundary Scan Order
100.	I/O	-	-	-	F17	-	AE22	558
101.	I/O	-	-	-	G16	-	AF23	564
102.	I/O	49	63	69	D19	K7	AD20	567
103.	I/O	50	64	70	E18	M5	AE21	570
104.	I/O	-	65	71	D20	R4	AF21	576
105.	I/O	-	66	72	G17	N5	AC19	579
106.	I/O	-	-	73	F18	P5	AD19	582
107.	I/O	-	-	74	H16	L6	AE20	588
108.	I/O	-	-	-	E19	-	AF20	591
109.	I/O	-	-	-	F19	-	AC18	594
	GND	51	67	75	E20	GND*	GND*	-
110.	I/O	52	68	76	H17	R5	AD18	600
111.	I/O	53	69	77	G18	M6	AE19	603
112.	I/O	54	70	78	G19	N6	AC17	606
113.	I/O	55	71	79	H18	P6	AD17	612
	VCC	-	-	80	F20	VCC*	VCC*	-
114.	I/O	-	72	81	J16	R6	AE17	615
115.	I/O	-	73	82	G20	M7	AE16	618
116.	I/O	-	-	-	H20	-	AF16	624
117.	I/O	-	-	-	J18	-	AC15	627
118.	I/O	-	-	84	J19	N7	AD15	630
119.	I/O	-	-	85	K16	P7	AE15	636
120.	I/O	56	74	86	J20	R7	AF15	639
121.	I/O	57	75	87	K17	L7	AD14	642
122.	I/O	58	76	88	K18	N8	AE14	648
123.	I/O (ERR, INIT)	59	77	89	K19	P8	AF14	651
	VCC	60	78	90	L20	VCC*	VCC*	-
	GND	61	79	91	K20	GND*	GND*	-
124.	I/O	62	80	92	L19	L8	AE13	660
125.	I/O	63	81	93	L18	P9	AC13	663
126.	I/O	64	82	94	L16	R9	AD13	672
127.	I/O	65	83	95	L17	N9	AF12	675
128.	I/O	-	84	96	M20	M9	AE12	678
129.	I/O	-	85	97	M19	L9	AD12	684
130.	I/O	-	-	-	N20	-	AC12	687
131.	I/O	-	-	-	M18	-	AF11	690
132.	I/O	-	-	99	N19	R10	AE11	696
133.	I/O	-	-	100	P20	P10	AD11	699
	VCC	-	-	101	T20	VCC*	VCC*	-
134.	I/O	66	86	102	N18	N10	AE9	702
135.	I/O	67	87	103	P19	K9	AD9	708
136.	I/O	68	88	104	N17	R11	AC10	711
137.	I/O	69	89	105	R19	P11	AF7	714
	GND	70	90	106	R20	GND*	GND*	-
138.	I/O	-	-	-	N16	-	AE8	720
139.	I/O	-	-	-	P18	-	AD8	723
140.	I/O	-	-	107	U20	M10	AC9	726
141.	I/O	-	-	108	P17	N11	AF6	732
142.	I/O	-	91	109	T19	R12	AE7	735
143.	I/O	-	92	110	R18	L10	AD7	738
144.	I/O	71	93	111	P16	P12	AE6	744
145.	I/O	72	94	112	V20	M11	AE5	747

Product Obsolete or Under Obsolescence



XC5200 Series Field Programmable Gate Arrays

Pin	Description	PQ160	HQ208	HQ240	PG299	BG225	BG352	Boundary Scan Order
146.	I/O	-	-	-	R17	-	AD6	750
147.	I/O	-	-	-	T18	-	AC7	756
148.	I/O	73	95	113	U19	R13	AF4	759
149.	I/O	74	96	114	V19	N12	AF3	768
150.	I/O	75	97	115	R16	P13	AD5	771
151.	I/O	76	98	116	T17	K10	AE3	774
152.	I/O	77	99	117	U18	R14	AD4	780
153.	I/O	78	100	118	X20	N13	AC5	783
	GND	79	101	119	W20	GND*	GND*	-
	DONE	80	103	120	V18	P14	AD3	-
	VCC	81	106	121	X19	VCC*	VCC*	-
	PROG	82	108	122	U17	M12	AC4	-
154.	I/O (D7)	83	109	123	W19	P15	AD2	792
155.	GCK3 (I/O)	84	110	124	W18	N14	AC3	795
156.	I/O	85	111	125	T15	L11	AB4	804
157.	I/O	86	112	126	U16	M13	AD1	807
158.	I/O	-	-	127	V17	N15	AA4	810
159.	I/O	-	-	128	X18	M14	AA3	816
160.	I/O	-	-	-	U15	-	AB2	819
161.	I/O	-	-	-	T14	-	AC1	828
162.	I/O (D6)	87	113	129	W17	J10	Y3	831
163.	I/O	88	114	130	V16	L12	AA2	834
164.	I/O	89	115	131	X17	M15	AA1	840
165.	I/O	90	116	132	U14	L13	W4	843
166.	I/O	-	117	133	V15	L14	W3	846
167.	I/O	-	118	134	T13	K11	Y2	852
168.	I/O	-	-	-	W16	-	Y1	855
169.	I/O	-	-	-	W15	-	V4	858
	GND	91	119	135	X16	GND*	GND*	-
170.	I/O	-	-	136	U13	L15	V3	864
171.	I/O	-	-	137	V14	K12	W2	867
172.	I/O	92	120	138	W14	K13	U4	870
173.	I/O	93	121	139	V13	K14	U3	876
	VCC	-	-	140	X15	VCC*	VCC*	-
174.	I/O (D5)	94	122	141	T12	K15	V2	879
175.	I/O (CS0)	95	123	142	X14	J12	V1	882
176.	I/O	-	-	-	X13	-	T1	888
177.	I/O	-	-	-	V12	-	R4	891
178.	I/O	-	124	144	W12	J13	R3	894
179.	I/O	-	125	145	T11	J14	R2	900
180.	I/O	96	126	146	X12	J15	R1	903
181.	I/O	97	127	147	U11	J11	P3	906
182.	I/O (D4)	98	128	148	V11	H13	P2	912
183.	I/O	99	129	149	W11	H14	P1	915
	VCC	100	130	150	X10	VCC*	VCC*	-
	GND	101	131	151	X11	GND*	GND*	-
184.	I/O (D3)	102	132	152	W10	H12	N2	924
185.	I/O (RS)	103	133	153	V10	H11	N4	927
186.	I/O	104	134	154	T10	G14	N3	936
187.	I/O	105	135	155	U10	G15	M1	939
188.	I/O	-	136	156	X9	G13	M2	942
189.	I/O	-	137	157	W9	G12	M3	948

Product Obsolete or Under Obsolescence



XC5200 Series Field Programmable Gate Arrays

Pin	Description	PQ160	HQ208	HQ240	PG299	BG225	BG352	Boundary Scan Order
235.	I/O	-	-	-	M5	-	B11	90
236.	I/O	-	-	-	P1	-	A11	93
237.	I/O (A4)	134	174	202	N1	A10	D12	99
238.	I/O (A5)	135	175	203	M3	D9	C12	102
239.	I/O	-	176	205	M2	C9	B12	105
240.	I/O	136	177	206	L5	B9	A12	111
241.	I/O	137	178	207	M1	A9	C13	114
242.	I/O	138	179	208	L4	E9	B13	117
243.	I/O (A6)	139	180	209	L3	C8	A13	126
244.	I/O (A7)	140	181	210	L2	B8	B14	129
	GND	141	182	211	L1	GND*	GND*	-

Additional No Connect (N.C.) Connections for HQ208 and HQ240 Packages

HQ208		HQ240
206	102	219
207	104	22
208	105	37
1	107	83
3	155	98
51	156	143
52	157	158
53	158	204
54	-	-

7

Notes: * Pins labeled VCC* are internally bonded to a VCC plane within the BG225 and BG352 packages. The external pins for the BG225 are: B2, D8, H15, R8, B14, R1, H1, and R15. The external pins for the BG352 are: A10, A17, B2, B25, D13, D19, D7, G23, H4, K1, K26, N23, P4, U1, U26, W23, Y4, AC14, AC20, AC8, AE2, AE25, AF10, and AF17.
Pins labeled GND* are internally bonded to a ground plane within the BG225 and BG352 packages. The external pins for the BG225 are: A1, D12, G7, G9, H6, H8, H10, J8, K8, A8, F8, G8, H2, H7, H9, J7, J9, M8. The external pins for the BG352 are: A1, A2, A5, A8, A14, A19, A22, A25, A26, B1, B26, E1, E26, H1, H26, N1, P26, W1, W26, AB1, AB26, AE1, AE26, AF1, AF13, AF19, AF2, AF22, AF25, AF26, AF5, AF8.

Boundary Scan Bit 0 = TDO.T
Boundary Scan Bit 1 = TDO.O
Boundary Scan Bit 1056 = BSCAN.UPD